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l s	TATEMENT I	BY /	APPLICANT	First Named Inventor	Karsten Buse	
_				Art Unit	N/A	
	(Use as many sh	eets as	necessary)	Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attorney Docket Number	20811/0204481-US0	

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Examiner Initials*	Cite No.1	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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	ВА	DE-10300080	07-22-2004	Deutsche Telekom Ag		1

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	CA	A.A. BUKHARAEV et al.: "Investigation of iron impurity centres in lithium niobate", Fizika Tverdogo Tela, USSR, Feb. 1976, ISSN 0367-3294, Soviet Physics - Solid State, USA, ISSN 0038-5654, XP-002320127 (1 page).		
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